

**Notice of References Cited**

Application/Control No.

09/522,510

Applicant(s)/Patent Under  
Reexamination  
WU, YOUFENG

Examiner

William H. Wood

Art Unit

2124

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,253,373	06-2001	Peri, Ramesh V.	717/150
	B	US-6,427,234	07-2002	Chambers et al.	717/140
	C	US-5,960,198	09-1999	Roediger et al.	717/130
	D	US-5,933,628	08-1999	Chang, Po-Hua	712/233
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input checked="" type="checkbox"/>	U	Wu et al., "Better Exploration of Region-Level Value Locality with Integrated Computation Reuse and Value Prediction", IEEE, 2001, 98-108.
<input checked="" type="checkbox"/>	V	Watterson et al., "Goal-Directed Value Profiling", Springer-Verlag Berlin Heidelberg, 2001, pp 319-333.
<input checked="" type="checkbox"/>	W	Sastry et al., "Characterizing Coarse-Grained Reuse of Computation", University of Wisconsin, Madison.
<input checked="" type="checkbox"/>	X	Sodani et al., "Dynamic Instruction Reuse", ACM, 1997.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input checked="" type="checkbox"/>	U	Hall, "Call Path Profiling", ACM, 1992, pp. 296-306.
<input checked="" type="checkbox"/>	V	Calder et al., "Value Profiling and Optimization", Journal of Instruction-Level Parallelism 1, 1999.
<input checked="" type="checkbox"/>	W	Connors et al., "Compiler-Directed Dynamic Computation Reuse: Rationale and Initial Results", IEEE, 1999, pp. 158-169. *Retransmitted for page numbered copy.
<input checked="" type="checkbox"/>	X	"Dictionary of Computing", Oxford University Press, Market House Books, 1996.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	M	US-			

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input checked="" type="checkbox"/>	U	Molina et al., "Dynamic Removal of Redundant Computations", Internatinal Conference on Supercomputing, 1999.
<input checked="" type="checkbox"/>	X	Lilja et al., "Exploiting Basic Block Value Locality with Block Reuse", 1998.
<input checked="" type="checkbox"/>	W	Gonzalez et al., "Trace-Level Reuse", 1999.
<input checked="" type="checkbox"/>	A	Lipasti et al., "Value Locality and Load Value Prediction", October 1996.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.